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IN THE UNITED STATES ELECTED/DESIGNATED OFFICE
OF THE UNITED STATES PATENT AND TRADEMARK OFFICE
UNDER THE PATENT COOPERATION TREATY-CHAPTER II

APPLICANT: Franz Hutner

DOCKET NO: 112740-147

SERIAL NO:

GROUP ART UNIT:

EXAMINER:

INTERNATIONAL APPLICATION NO: PCT/DE99/02130

INTERNATIONAL FILING DATE: 09 July 1999

INVENTION: INTEGRATED CIRCUIT WITH BUILT-IN MODULE TEST

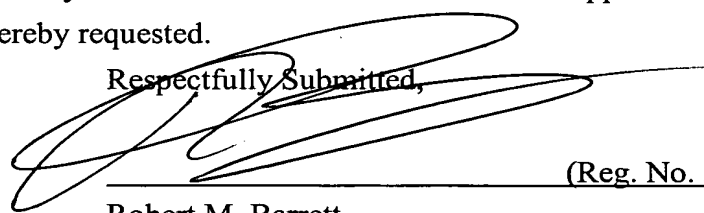
Assistant Commissioner for Patents,
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

In accordance with the provisions of 37 CFR §1.56, Applicant requests that citation and examination of the references listed on Form PTO-1449, copies of which are enclosed herewith in accordance with 37 CFR §1.98, be made during the course of examination of the above-identified application for United States Patent.

Applicant respectfully submits that the claimed invention is distinguishable and non-obvious over the enclosed references, taken singly or in combination. Accordingly, early consideration and allowance of the application, including the claims, are hereby requested.

Respectfully Submitted,



(Reg. No. 30,142)

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Sheet 1 of 1

37 CFR 1.501
 INFORMATION DISCLOSURE STATEMENT
 IN A PATENT
 (use several sheets if necessary)

Docket No.
 112740-147

Serial No.

Applicant:

Hutner

Filing Date

Group Art Unit

U.S. PATENT DOCUMENTS

Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If appropriate
M.D.	AA	4,519,078	5-21-85	Komonytsky			
M.D.	AB	5,677,916	10-14-97	Nozuyama			
M.D.	AC	5,710,934	1-20-98	Bona et al.			
M.D.	AD	5,781,718	7-14-98	Nguyen			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							
	AQ							
	AR							
	AS							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

M.P.	AT	Patent Abstracts of Japan - 08125024 - 17 5 96
	AU	
	AV	
	AW	

Examiner

Matt Dooy

Date Considered

4/26/04

***EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.